

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/662,596	CHO ET AL.	
	<b>Examiner</b> DINH T. LE	<b>Art Unit</b> 2816	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
327,331	see above	10/30/2007	DL
714,375	see above	10/30/2007	DL